

**Search Notes**

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Alain L. Bashore

Applicant(s)/Patent under  
Reexamination

TAKAHASHI ET AL.

Art Unit

1762

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
427	126,131	11/9/2006	AB
428	694st	11/9/2006	AB
428	694sl	11/9/2006	AB
428/694bs		11/9/2006	ab

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
previos search updated	11/9/2006	ab